

#### **AMENDMENTS TO THE SPECIFICATION:**

Please amend paragraph [0038] as indicated below.

**[0038]** The base band output signal 140 is delivered to a test control unit (TCU) 146, which, controls the test arrangement, for example. The test control unit 146 may include a test logic unit (TLU) 152, which manages the routing of the BB input test signal 142 to a test signal generator 130 and the BB output test signal 140 from a desired RF device 132 to a desired output test access port of the test control unit 146. The test control unit 146 may be implemented with binary registers, memory means, buses and a processing unit. A detailed structure of a test control unit 146 can be found in the cited IEEE-1949.4 1149.4 standard, for example.

Please amend paragraph [0062] as indicated below.

**[0062]** The down-converter unit 128, the test signal generator 130, the digital test module 172, the analog test module 174, the digital test access port 154, and the analog test access port 156 form a test structure 184 shown with a dashed block. The test structure 184 may be based on a standardized architecture, such as IEEE-1194.4 1149.4.

Please amend paragraph [0063] as indicated below.

**[0063]** With reference to Figure 2, an example of the test arrangement based on the IEEE-1194.4 1149.4 standard is shown. The mixed signal part 200 includes a digital device 204 under test (DDUT) and a BB analog device 206 under test (ADUT). The digital device 204 and the BB analog device 206 are probed by a Digital Boundary Module 208 (DBM) and an Analog Boundary Module 210 (ABM), respectively.